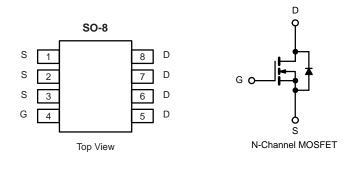


IRF7853TRPBF-VB Datasheet

N-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)	
100	0.020 at V _{GS} = 10 V	10.4	23 nC	
100	0.027 at V _{GS} = 8 V	9.5	23110	



FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- Extremely Low Q_{gd} for Switching Losses
- 100 % R_g Tested
- 100 % Avalanche Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

• Primary Side Switch



COMPLIANT HALOGEN FREE Available

Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	100	V
Gate-Source Voltage		V _{GS}	± 20	v
	T _C = 25 °C		10.4	
Continuous Drain Current (T 150 °C)	T _C = 70 °C		9.1	
Continuous Drain Current ($T_J = 150 \ ^{\circ}C$)	T _A = 25 °C		8.5 ^{b, c}	
	T _A = 70 °C		7.5 ^{b, c}	Α
Pulsed Drain Current		I _{DM}	50	A
Continuous Source-Drain Diode Current	T _C = 25 °C		4.5	
	T _A = 25 °C	I _S	2.6 ^{b, c}	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	20	
Single Pulse Avalanche Energy		E _{AS}	20	mJ
	T _C = 25 °C		5.9	
Maximum Power Dissinction	T _C = 70 °C		3.8	W
Maximum Power Dissipation	T _A = 25 °C	P _D —	3.1 ^{b, c}	vv
	T _A = 70 °C	1 –	2 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATINGS						
	Symbol	Typical	Maximum	Unit		
t ≤ 10 s	R _{thJA}	33	40	°C/W		
Steady State	R _{thJF}	17	21	- C/VV		
	t ≤ 10 s	Symbol t ≤ 10 s R _{thJA}	Symbol Typical t ≤ 10 s R _{thJA} 33	Symbol Typical Maximum t ≤ 10 s R _{thJA} 33 40		

Notes:

a. Based on T_C = 25 °C.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under steady state conditions is 80 °C/W.

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static					•		
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	100			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			172			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 10		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.5		4.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zana Olata Malla na Dasia Olamani		$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1		
Zero Gate Voltage Drain Current	DSS	$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 \text{ °C}$			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 10 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	30			Α	
	_	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$		0.020		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 8 V, I_{D} = 5 A$		0.027			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 5 A		23		S	
Dynamic ^b					•	•	
Input Capacitance	C _{iss}			1735			
Output Capacitance	C _{oss}	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz		160		pF	
Reverse Transfer Capacitance	C _{rss}			37			
Total Gate Charge		$V_{DS} = 75 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$		28.5	43		
	Qg			23	35		
Gate-Source Charge	Q _{gs}	$V_{DS} = 75 \text{ V}, V_{GS} = 8 \text{ V}, I_{D} = 5 \text{ A}$		8		nC	
Gate-Drain Charge	Q _{gd}			6.5			
Gate Resistance	R _q	f = 1 MHz		0.85	1.3	Ω	
Turn-on Delay Time	t _{d(on)}			14	21		
Rise Time	t _r	$V_{DD} = 50 \text{ V}, \text{ R}_{\text{I}} = 10 \Omega$		12	18		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ Å}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		22	33		
Fall Time	t _f			6	10		
Turn-On Delay Time	t _{d(on)}			16	24	ns	
Rise Time	t _r	V_{DD} = 50 V, R_{L} = 10 Ω		12	18	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 8 \text{ V}, R_g = 1 \Omega$		20	30		
Fall Time	t _f			7	12		
Drain-Source Body Diode Characteristi	cs			•	•	•	
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			7.7	٨	
Pulse Diode Forward Current ^a	I _{SM}				50	A	
Body Diode Voltage	V _{SD}	I _S = 2.6 A		0.77	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			63	95	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			110	165	nC	
Reverse Recovery Fall Time	t _a	$I_F = 5 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 \text{ °C}$		49			
Reverse Recovery Rise Time	t _b			14		ns	

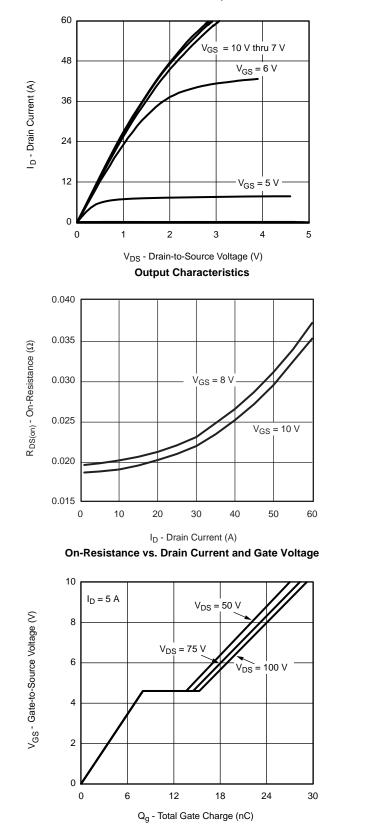
Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

a. Guaranteed by design, not subject to production testing.

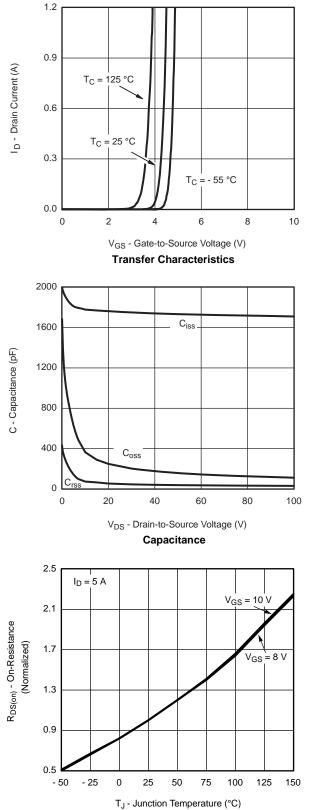
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





Gate Charge

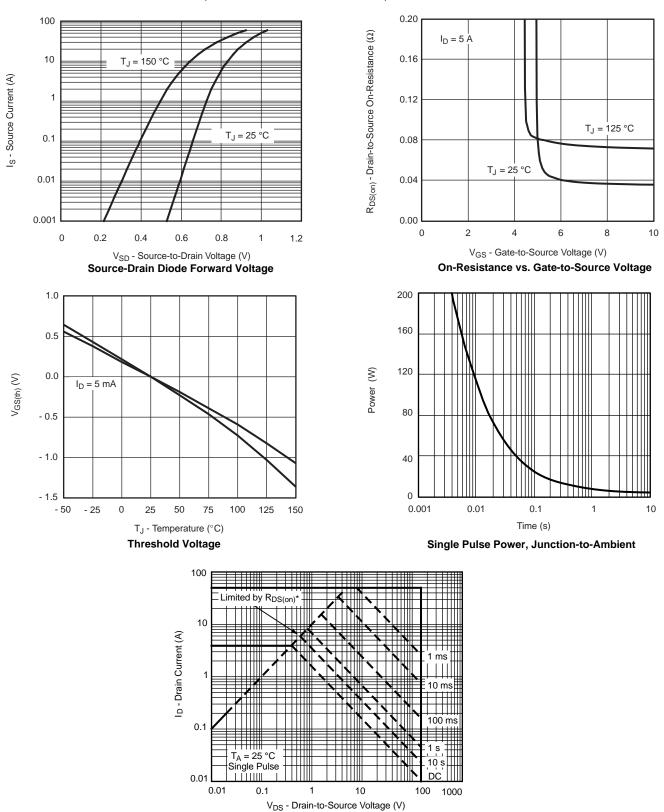
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



On-Resistance vs. Junction Temperature

服务热线:400-655-8788



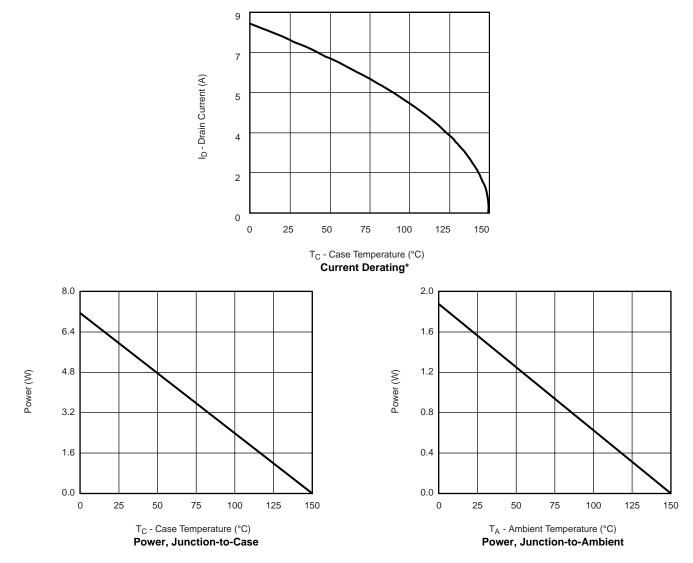


* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified Safe Operating Area, Junction-to-Ambient

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



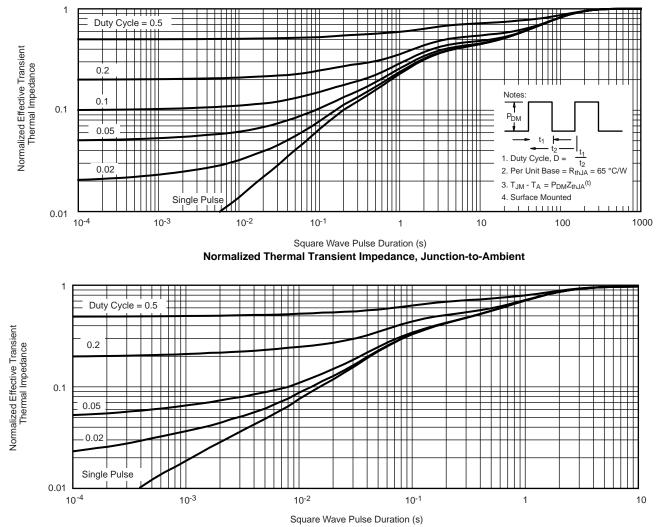
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

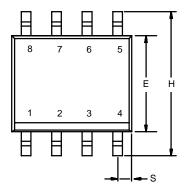


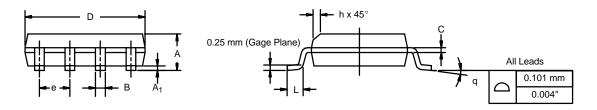
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012

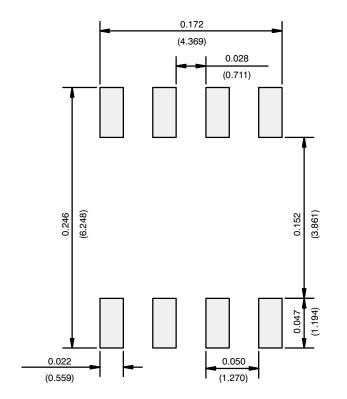




	MILLIM	IETERS	INC	INCHES		
DIM	Min	Мах	Min	Max		
A	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27 BSC		0.050) BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498						



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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